



Friday, March 18, 2022

12:15

We are pleased to invite you to join AFM Seminar, **A modern approach to study sample physiochemical properties with the use of atomic force microscopy**. During the 50-minute presentation, Dr Peter De Wolf (Bruker) will illustrate how advanced AFM provides effective metrology solutions for materials science. The presentation will focus mainly on the research application.

[Click here to join the meeting](#)



Peter Dewolf, Ph.D.
Application Director
Bruker Nano Surfaces

Peter De Wolf is application director at Bruker Nano Surfaces, leading an international team of application scientists and laboratories with various locations worldwide, covering all applications related to Scanning Probe Microscopy (SPM). He obtained his PhD from IMEC, Belgium on the development of new SPM methods for 2D carrier profiling in semiconductors and has more than 25 years of experience on SPM. He is the author and co-author of over 30 publications related to electrical characterization using SPM. He also owns several SPM patents, and developed several new SPM modes for electrical characterization, including Scanning Spreading Resistance Microscopy (SSRM), Tunneling-AFM (TUNA), and DataCube methods.